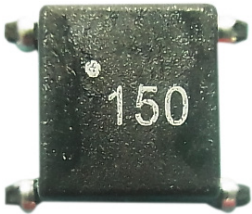


Common Mode Choke

RoHS
Compliant

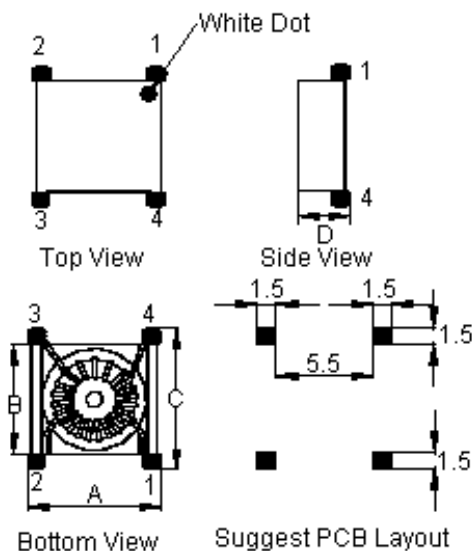
Electrical Characteristics (at 25°C)



1kHz 0.25V	L_{1-4}	15 μ H +50% -35%
	L_{2-3}	
	$L_{1-4}-L_{2-3}$	2 μ H (Max.)
at 25°C	DCR_{1-4}	35m Ω (Max.)
	DCR_{2-3}	
100MHz	Z	350 Ω (Typical)
Coil-Coil DC 1,000 2mA	Hi-pot	3S (Min.)
1kHz 0.25V	Rated Current	500mA (Max.)
	Rated Voltage	50V (Typical)

Operating temperature: -20°C to +85°C

Configurations and Dimensions



A	8.3 \pm 0.5mm
B	7 \pm 0.5mm
C	10 \pm 0.5mm
D	5 \pm 0.5mm

Dimensions : Millimetres

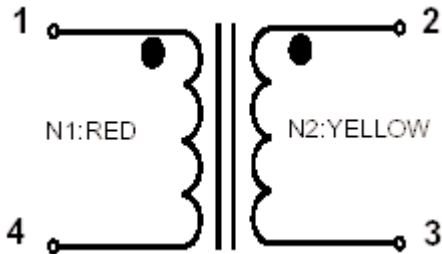
Test Data for Mechanical

Test Item	A mm	B mm	C mm	D mm
Specification	8.3 \pm 0.5	7 \pm 0.5	10 \pm 0.5	5 \pm 0.5
1	8.35	7.02	10.01	4.93
2	8.36	7.06	10.33	4.98
3	8.29	7.03	10.06	4.95
4	8.32	7.02	10.02	4.9
5	8.31	7.04	10.12	4.95
Average	8.33	7.03	10.11	4.94

Common Mode Choke



Schematic Diagram



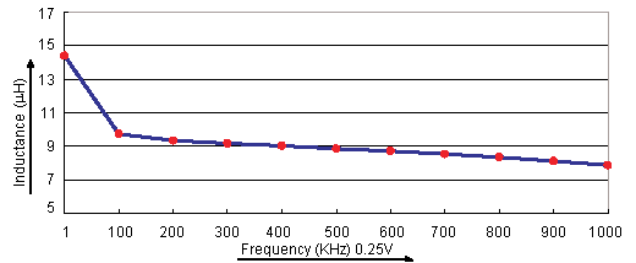
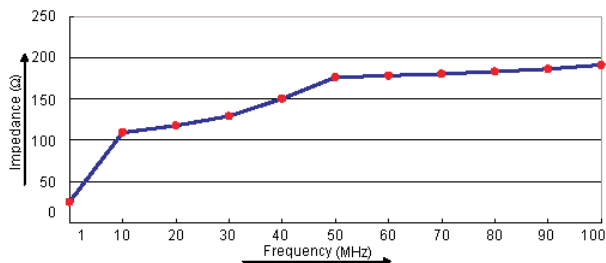
Note:

- 1-4.Wire Ø0.3mm × 1P 2UEWF 155°C × 5TS (Reference)
- 2-3.Wire Ø0.3mm × 1P 2UEWF 155°C × 5TS (Reference)

Test Data for Electrical

Test Item	L_{1-4} μH	L_{2-3} μH	$L_{1-4-2-3}$ μH	DCR_{1-4} $\text{m}\Omega$	DCR_{2-3} $\text{m}\Omega$	Z Ω	Hi-pot S
Condition	1KHz 0.25V	1KHz 0.25V	1KHz 0.25V	at 25°C	at 25°C	100MHz	Coil-Coil DC 1,000 2mA
Specification	15 +50% -35%	15 +50% -35%	2 (Max.)	35 (Max.)	35 (Max.)	350 (Typical)	3 (Min.)
1	17.8	17.7	0.1	14.67	14.4	191.1	OK
2	15.8	15.7		14.64	14.43	193.5	OK
3	16.6	16.5		13.93	14.29	194.8	OK
4	14.2	14.2	0	14.4	14.87	182.5	OK
5	17.1	17	0.1	14.64	14.41	193.4	OK
Average	16.3	16.22	0.08	14.46	14.48	191.06	OK

Electric Characteristics



Common Mode Choke



Reliability Test

Test Item	Specifications	Test Method and Remarks
Operating temperature range	-20°C to +85°C	Including temperature rise due to self-generated heat
Storage condition	Ambient temperature : 0°C to 40°C Humidity : Below 70%RH	To maintain the solderability of terminal electrodes, care must be taken to control temperature and humidity in the storage area.
Moisture sensitivity	Appearance : No abnormality No damage DCR change : Within ±20% Inductance change : Within ±20%	According to J-STD-020B level 3 Test condition : 60°C 60% RH Test duration : 40 hours Recovery : 1 to 2 hours of recovery under the standard condition after the removal from the test chamber.
Solderability	All termination shall exhibit a continuous solder coating free from defects for a minimum of 90% of the surface area of any individual lead.	According to J-STD-002B Steam aging category : 97°C 98% RH Steam aging duration : 8 hours Solder : Lead-free solder Solder temperature : 260 ±5°C Dip time : 5 +0/-0.5 seconds.

Material List

No.	Item	Material Description
1	Core	S2K T4.3 × 2.5 × 2.8
2	Wire	Ø0.3mm × 2P 2UEWF 155°C
3	Solder (Lead Free)	Sn99.3%Cu0.7%
4	Base	BG406-1 LCP4008

Part Number Table

Description	Part Number
Choke, common mode, 15µH, 0.5A	MCBS3019P-150U

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